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CCS H 17

YS

**NONFERROUS METALS INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

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**Testing of surface particles on wafer packaging boxes - Liquid
particle counting method
(English Translation)**

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What this standard covers

This standard specifies the method for testing the surface particles of wafer packaging boxes with a liquid particle counter. This standard is applicable to the test of particle cleanliness of silicon polished wafers, silicon epitaxial wafers, SOI wafers and other materials of semiconductor wafer packaging boxes with diameters of 100mm, 125mm, 150mm, 200mm, and 300mm.

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